

IRFPF30PBF-VB Datasheet

N-Channel 900V (D-S) Super Junction Power MOSFET

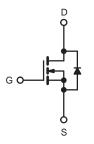
PRODUCT SUMMARY						
V _{DS} (V)	90	900				
R _{DS(on)} (Ω)	V _{GS} = 10 V	1.3				
Q _g (Max.) (nC)	200	200				
Q _{gs} (nC)	24	24				
Q _{gd} (nC)	110	110				
Configuration	Sing	Single				

FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC







N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V_{DS}	900	V	
Gate-Source Voltage			V_{GS}	± 20	∃ ′	
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C		5		
Continuous Drain Current	VGS at 10 V	T _C = 100 °C		3.9	A	
Pulsed Drain Current ^a			I _{DM}	21		
Linear Derating Factor				1.5	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	770	mJ	
Repetitive Avalanche Currenta	I _{AR}	7.8	Α			
Repetitive Avalanche Energy ^a	E _{AR}	19	mJ			
Maximum Power Dissipation $T_C = 25 ^{\circ}C$			P _D	190	W	
Peak Diode Recovery dV/dtc	dV/dt	2.0	V/ns			
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature) for 10 s				300 ^d		
Mounting Torque	6 32 or I	12 corow		10	lbf ⋅ in	
Mounting Torque	6-32 or M3 screw			1.1	N · m	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. $V_{DD}=50~V$, starting $T_J=25~^{\circ}C$, L=23~mH, $R_g=25~\Omega$, $I_{AS}=7.8~A$ (see fig. 12). c. $I_{SD}\leq7.8~A$, $dI/dt\leq140~A/\mu s$, $V_{DD}\leq600~V$, $T_J\leq150~^{\circ}C$. d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	40		
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.24	-	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.65		

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static						•	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$		900	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C, I _D = 1 mA	-	0.98	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} :	= V _{GS} , I _D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}		V _{GS} = ± 20 V	-	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}		= 800 V, V _{GS} = 0 V V, V _{GS} = 0 V, T _J = 125 °C	-	-	100 500	μΑ
Drain-Source On-State Resistance	R _{DS(on)}		$I_D = 3.7 \text{ A}^b$		1.3	-	Ω
Forward Transconductance	9fs		= 100 V, I _D = 3.7 A ^b	5.6	-	_	S
Dynamic	gis	1 105 -	- 100 V, ID = 0.7 7	0.0			
Input Capacitance	C _{iss}			_	3100	l -	
Output Capacitance	C _{oss}	1	$V_{GS} = 0 V$, $V_{DS} = 25 V$,	-	800	-	pF
Reverse Transfer Capacitance	C _{rss}	f = 1	f = 1.0 MHz, see fig. 5		490	-	- "
Total Gate Charge	Qq	1		-	-	200	
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$I_D = 3.8 \text{ A}, V_{DS} = 400 \text{ V},$	-	-	24	nC
Gate-Drain Charge	Q _{gd}	see fig. 6 and 13 ^b		-	-	110	1
Turn-On Delay Time	t _{d(on)}	V_{DD} = 400 V, I_{D} = 3.8 A, R_{g} = 6.2 Ω , R_{D} = 52 Ω see fig. 10 ^b		-	19	-	ns ns
Rise Time	t _r			-	38	-	
Turn-Off Delay Time	t _{d(off)}			-	120	-	
Fall Time	t _f			-	39	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	5.0	-	-11
Internal Source Inductance	L _S			-	13	-	- nH
Drain-Source Body Diode Characteristic	s				l	•	
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	5.0	_
Pulsed Diode Forward Current ^a	I _{SM}			-	-	21	A
Body Diode Voltage	V _{SD}	T _J = 25 °C, I _S = 3.8 A, V _{GS} = 0 V ^b		-	-	1.8	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 3.8 A, dl/dt = 100 A/μs ^b		-	650	980	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	3.8	5.7	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L _S and L _I			L _D)		

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width \leq 300 µs; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

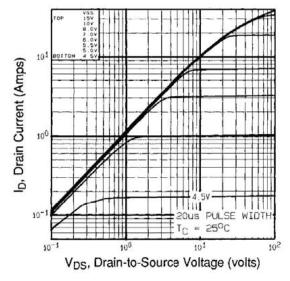


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

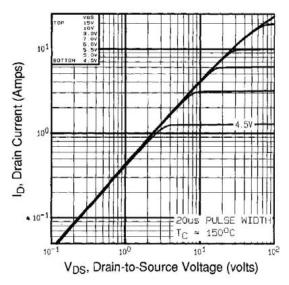


Fig. 2 - Typical Output Characteristics, $T_C = 150$ °C

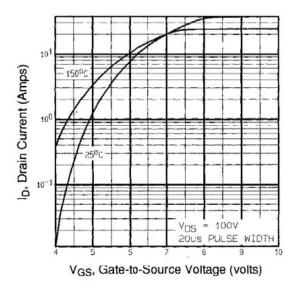


Fig. 3 - Typical Transfer Characteristics

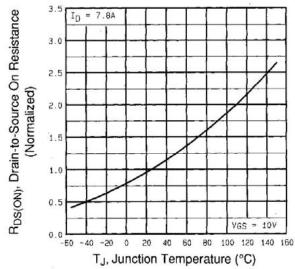


Fig. 4 - Normalized On-Resistance vs. Temperature



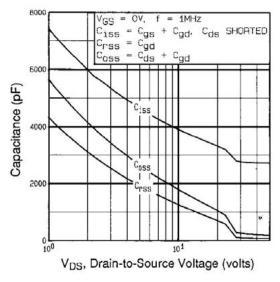


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

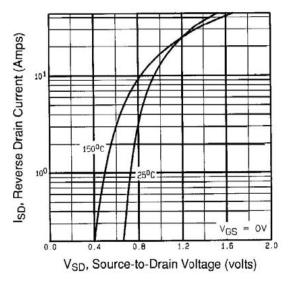


Fig. 7 - Typical Source-Drain Diode Forward Voltage

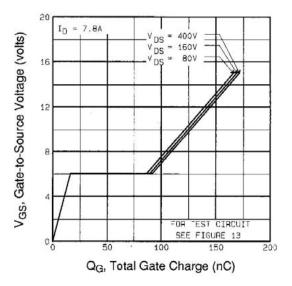


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

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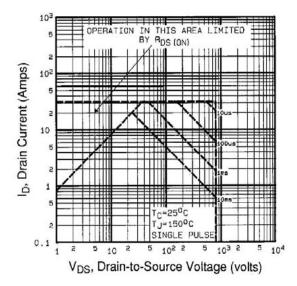


Fig. 8 - Maximum Safe Operating Area



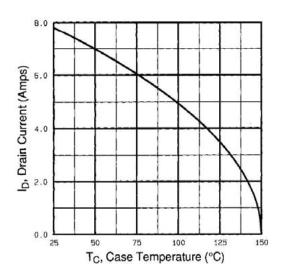


Fig. 9 - Maximum Drain Current vs. Case Temperature

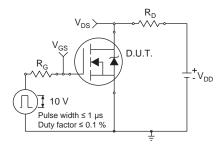


Fig. 10a - Switching Time Test Circuit

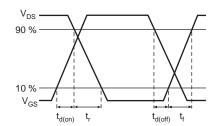


Fig. 10b - Switching Time Waveforms

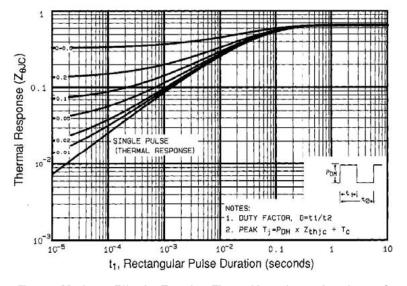


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



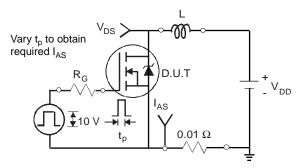


Fig. 12a - Unclamped Inductive Test Circuit

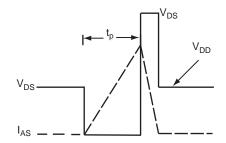


Fig. 12b - Unclamped Inductive Waveforms

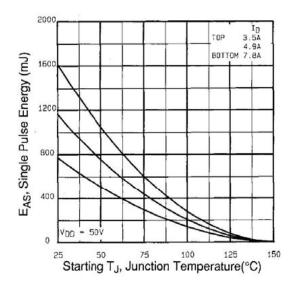


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

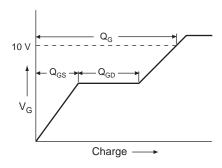


Fig. 13a - Basic Gate Charge Waveform

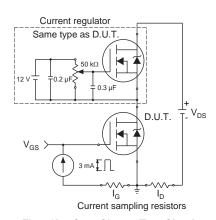
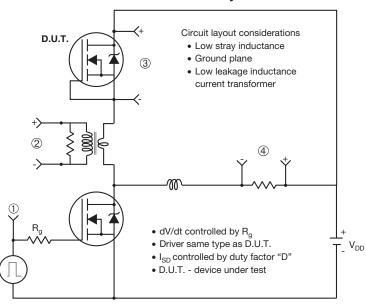


Fig. 13b - Gate Charge Test Circuit



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Peak Diode Recovery dV/dt Test Circuit



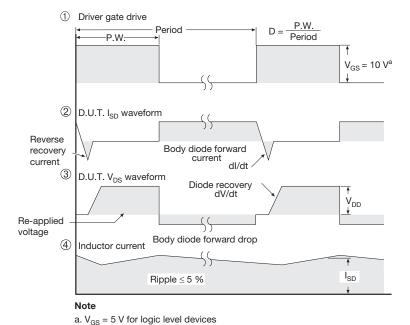
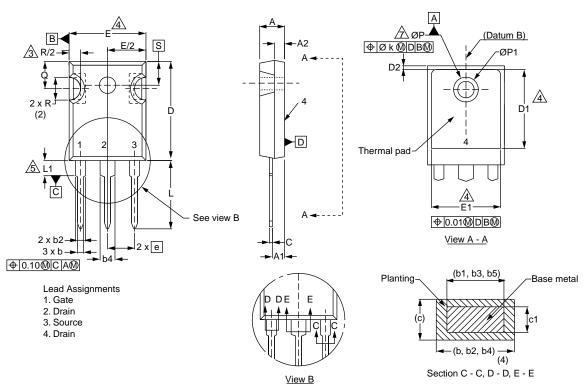


Fig. 14 - For N-Channel



TO-247AC (High Voltage)



	MILLIM	IETERS	INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
Α	4.58	5.31	0.180	0.209
A1	2.21	2.59	0.087	0.102
A2	1.17	2.49	0.046	0.098
b	0.99	1.40	0.039	0.055
b1	0.99	1.35	0.039	0.053
b2	1.53	2.39	0.060	0.094
b3	1.65	2.37	0.065	0.093
b4	2.42	3.43	0.095	0.135
b5	2.59	3.38	0.102	0.133
С	0.38	0.86	0.015	0.034
c1	0.38	0.76	0.015	0.030
D	19.71	20.82	0.776	0.820
D1	13.08	-	0.515	-

	MILLIMETERS		INC	HES	
DIM.	MIN.	MAX.	MIN.	MAX.	
D2	0.51	1.30	0.020	0.051	
Е	15.29	15.87	0.602	0.625	
E1	13.72	ı	0.540	1	
е	5.46	5.46 BSC 0.215 BS0		BSC	
Øk	0.2	0.254		0.010	
L	14.20	16.25	0.559	0.640	
L1	3.71	4.29	0.146	0.169	
N	7.62	7.62 BSC		0.300 BSC	
ØΡ	3.51	3.66	0.138	0.144	
Ø P1	-	7.39	ı	0.291	
Q	5.31	5.69	0.209	0.224	
R	4.52	5.49	0.178	0.216	
S	5.51 BSC		0.217	BSC	



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